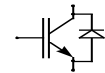


# Technische Information / Technical Information

IGBT-Module  
IGBT-Modules

## FZ 800 R 33 KF2

eupec



**vorläufiges Datenblatt**  
**preliminary datasheet**

### Höchstzulässige Werte / Maximum rated values

#### Elektrische Eigenschaften / Electrical properties

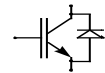
Kollektor-Emitter-Sperrspannung collector-emitter voltage	$T_j = 25^\circ\text{C}$ $T_j = -25^\circ\text{C}$	$V_{\text{CES}}$	3300 3300	V
Kollektor-Dauergleichstrom DC-collector current	$T_C = 80^\circ\text{C}$ $T_C = 25^\circ\text{C}$	$I_{\text{C,nom.}}$ $I_{\text{C}}$	800 1200	A A
Periodischer Kollektor Spitzenstrom repetitive peak collector current	$t_p = 1 \text{ ms}, T_C = 80^\circ\text{C}$	$I_{\text{CRM}}$	1600	A
Gesamt-Verlustleistung total power dissipation	$T_C = 25^\circ\text{C}$ , Transistor	$P_{\text{tot}}$	9,6	kW
Gate-Emitter-Spitzenspannung gate-emitter peak voltage		$V_{\text{GES}}$	+/- 20V	V
Dauergleichstrom DC forward current		$I_{\text{F}}$	800	A
Periodischer Spitzenstrom repetitive peak forw. current	$t_p = 1 \text{ ms}$	$I_{\text{FRM}}$	1600	A
Grenzlastintegral der Diode $I^2t$ - value, Diode	$V_R = 0\text{V}, t_p = 10\text{ms}, T_{vj} = 125^\circ\text{C}$	$I^2t$	222.200	$\text{A}^2\text{s}$
Spitzenverlustleistung der Diode maximum power dissipation diode	$T_j = 125^\circ\text{C}$	$P_{\text{ROM}}$	800	kW
Isolations-Prüfspannung insulation test voltage	RMS, $f = 50 \text{ Hz}, t = 1 \text{ min.}$	$V_{\text{ISOL}}$	6.000	V
Teilentladungs-Aussetzspannung partial discharge extinction voltage	RMS, $f = 50 \text{ Hz}, Q_{\text{PD}} \leq 10 \text{ pC}$ (acc. to IEC 1287)	$V_{\text{ISOL}}$	2.600	V

### Charakteristische Werte / Characteristic values

#### Transistor / Transistor

			min.	typ.	max.	
Kollektor-Emitter Sättigungsspannung collector-emitter saturation voltage	$I_{\text{C}} = 800\text{A}, V_{\text{GE}} = 15\text{V}, T_{vj} = 25^\circ\text{C}$	$V_{\text{CE sat}}$	-	3,40	4,25	V
	$I_{\text{C}} = 800\text{A}, V_{\text{GE}} = 15\text{V}, T_{vj} = 125^\circ\text{C}$		-	4,30	-	V
Gate-Schwellenspannung gate threshold voltage	$I_{\text{C}} = 80 \text{ mA}, V_{\text{CE}} = V_{\text{GE}}, T_{vj} = 25^\circ\text{C}$	$V_{\text{GE(th)}}$	4,2	5,1	6,0	V
Eingangskapazität input capacitance	$f = 1\text{MHz}, T_{vj} = 25^\circ\text{C}, V_{\text{CE}} = 25\text{V}, V_{\text{GE}} = 0\text{V}$	$C_{\text{ies}}$	-	100	-	nF
Rückwirkungskapazität reverse transfer capacitance	$f = 1\text{MHz}, T_{vj} = 25^\circ\text{C}, V_{\text{CE}} = 25\text{V}, V_{\text{GE}} = 0\text{V}$	$C_{\text{res}}$	-	5,4	-	nF
Gateladung gate charge	$V_{\text{GE}} = -15\text{V} \dots +15\text{V}, V_{\text{CE}} = 1800\text{V}$	$Q_{\text{G}}$	-	15	-	$\mu\text{C}$
Kollektor-Emitter Reststrom collector-emitter cut-off current	$V_{\text{CE}} = 3300\text{V}, V_{\text{GE}} = 0\text{V}, T_{vj} = 25^\circ\text{C}$	$I_{\text{CES}}$	-	20	-	$\mu\text{A}$
	$V_{\text{CE}} = 3300\text{V}, V_{\text{GE}} = 0\text{V}, T_{vj} = 125^\circ\text{C}$		-	40	-	$\text{mA}$
Gate-Emitter Reststrom gate-emitter leakage current	$V_{\text{CE}} = 0\text{V}, V_{\text{GE}} = 20\text{V}, T_{vj} = 25^\circ\text{C}$	$I_{\text{GES}}$	-	-	400	$\text{nA}$

prepared by: Jürgen Göttert	date of publication : 16.11.98
approved by: Hubert Ludwig	revision: 2

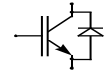


### Charakteristische Werte / Characteristic values

Transistor / Transistor			min.	typ.	max.	
Einschaltverzögerungszeit (ind. Last) turn on delay time (inductive load)	$I_C = 800 \text{ A}, V_{CE} = 1800 \text{ V}$	$t_{d,on}$	-	370	-	ns
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 25^\circ \text{ C}$					
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 125^\circ \text{ C}$					
Anstiegszeit (induktive Last) rise time (inductive load)	$I_C = 800 \text{ A}, V_{CE} = 1800 \text{ V}$	$t_r$	-	250	-	ns
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 25^\circ \text{ C}$					
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 125^\circ \text{ C}$					
Abschaltverzögerungszeit (ind. Last) turn off delay time (inductive load)	$I_C = 800 \text{ A}, V_{CE} = 1800 \text{ V}$	$t_{d,off}$	-	1550	-	ns
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 25^\circ \text{ C}$					
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 125^\circ \text{ C}$					
Fallzeit (induktive Last) fall time (inductive load)	$I_C = 800 \text{ A}, V_{CE} = 1800 \text{ V}$	$t_f$	-	200	-	ns
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 25^\circ \text{ C}$					
	$V_{GE} = \pm 15 \text{ V}, R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 125^\circ \text{ C}$					
Einschaltverlustenergie pro Puls turn-on energy loss per pulse	$I_C = 800 \text{ A}, V_{CE} = 1800 \text{ V}, V_{GE} = 15 \text{ V}$ $R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 125^\circ \text{ C}, L_S = 40 \text{ nH}$	$E_{on}$	-	1920	-	mWs
Abschaltverlustenergie pro Puls turn-off energy loss per pulse	$I_C = 800 \text{ A}, V_{CE} = 1800 \text{ V}, V_{GE} = 15 \text{ V}$ $R_G = 1,8 \Omega, C_{GE} = 150 \text{ nF}, T_{vj} = 125^\circ \text{ C}, L_S = 40 \text{ nH}$	$E_{off}$	-	1020	-	mWs
Kurzschlußverhalten SC Data	$t_p \leq 10 \mu\text{sec}, V_{GE} \leq 15 \text{ V}$	$I_{SC}$	-	4000	-	A
	$T_{vj} \leq 125^\circ \text{ C}, V_{CC} = 2500 \text{ V}, V_{CEmax} = V_{CES} - L_{sCE} \cdot di/dt$					
Modulinduktivität stray inductance module		$L_{sCE}$	-	12	-	nH
Modul-Leitungswiderstand, Anschlüsse - Chip lead resistance, terminals - chip		$R_{CC+EE}$	-	0,08	-	mΩ

### Charakteristische Werte / Characteristic values

Diode / Diode			min.	typ.	max.	
Durchlaßspannung forward voltage	$I_F = 800 \text{ A}, V_{GE} = 0 \text{ V}, T_{vj} = 25^\circ \text{ C}$	$V_F$	-	2,80	3,50	V
	$I_F = 800 \text{ A}, V_{GE} = 0 \text{ V}, T_{vj} = 125^\circ \text{ C}$					
Rückstromspitze peak reverse recovery current	$I_F = 800 \text{ A}, -di_F/dt = 3500 \text{ A}/\mu\text{sec}$	$I_{RM}$	-	880	-	A
	$V_R = 1800 \text{ V}, V_{GE} = -10 \text{ V}, T_{vj} = 25^\circ \text{ C}$					
	$V_R = 1800 \text{ V}, V_{GE} = -10 \text{ V}, T_{vj} = 125^\circ \text{ C}$					
Sperrverzögerungsladung recovered charge	$I_F = 800 \text{ A}, -di_F/dt = 3500 \text{ A}/\mu\text{sec}$	$Q_r$	-	500	-	μAs
	$V_R = 1800 \text{ V}, V_{GE} = -10 \text{ V}, T_{vj} = 25^\circ \text{ C}$					
	$V_R = 1800 \text{ V}, V_{GE} = -10 \text{ V}, T_{vj} = 125^\circ \text{ C}$					
Abschaltenergie pro Puls reverse recovery energy	$I_F = 800 \text{ A}, -di_F/dt = 3500 \text{ A}/\mu\text{sec}$	$E_{rec}$	-	-	-	mWs
	$V_R = 1800 \text{ V}, V_{GE} = -10 \text{ V}, T_{vj} = 25^\circ \text{ C}$					
	$V_R = 1800 \text{ V}, V_{GE} = -10 \text{ V}, T_{vj} = 125^\circ \text{ C}$					



**vorläufiges Datenblatt  
preliminary datasheet**

**Thermische Eigenschaften / Thermal properties**

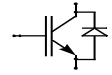
			min.	typ.	max.	
Innerer Wärmewiderstand thermal resistance, junction to case	Transistor / transistor, DC	$R_{thJC}$	-	-	0,013	K/W
	Diode/Diode, DC		-	-	0,026	K/W
Übergangs-Wärmewiderstand thermal resistance, case to heatsink	pro Modul / per module $\lambda_{Paste} = 1 \text{ W/m}^2\text{K} / \lambda_{grease} = 1 \text{ W/m}^2\text{K}$	$R_{thCK}$	-	0,006	-	K/W
Höchstzulässige Sperrschichttemperatur maximum junction temperature		$T_{vj}$	-	-	150	°C
Betriebstemperatur operation temperature		$T_{op}$	-40	-	125	°C
Lagertemperatur storage temperature		$T_{stg}$	-40	-	125	°C

**Mechanische Eigenschaften / Mechanical properties**

Gehäuse, siehe Anlage case, see appendix					
Material Modulgrundplatte material of module baseplate				AlSiC	
Innere Isolation internal insulation				AlN	
Kriechstrecke creepage distance				32,2	mm
Luftstrecke clearance				19,1	mm
CTI comperative tracking index				> 400	
Anzugsdrehmoment f. mech. Befestigung mounting torque		M1		5	Nm
Anzugsdrehmoment f. elektr. Anschlüsse terminal connection torque	terminals M4	M2		2	Nm
	terminals M8			8 .. 10	Nm
Gewicht weight		G		1000	g

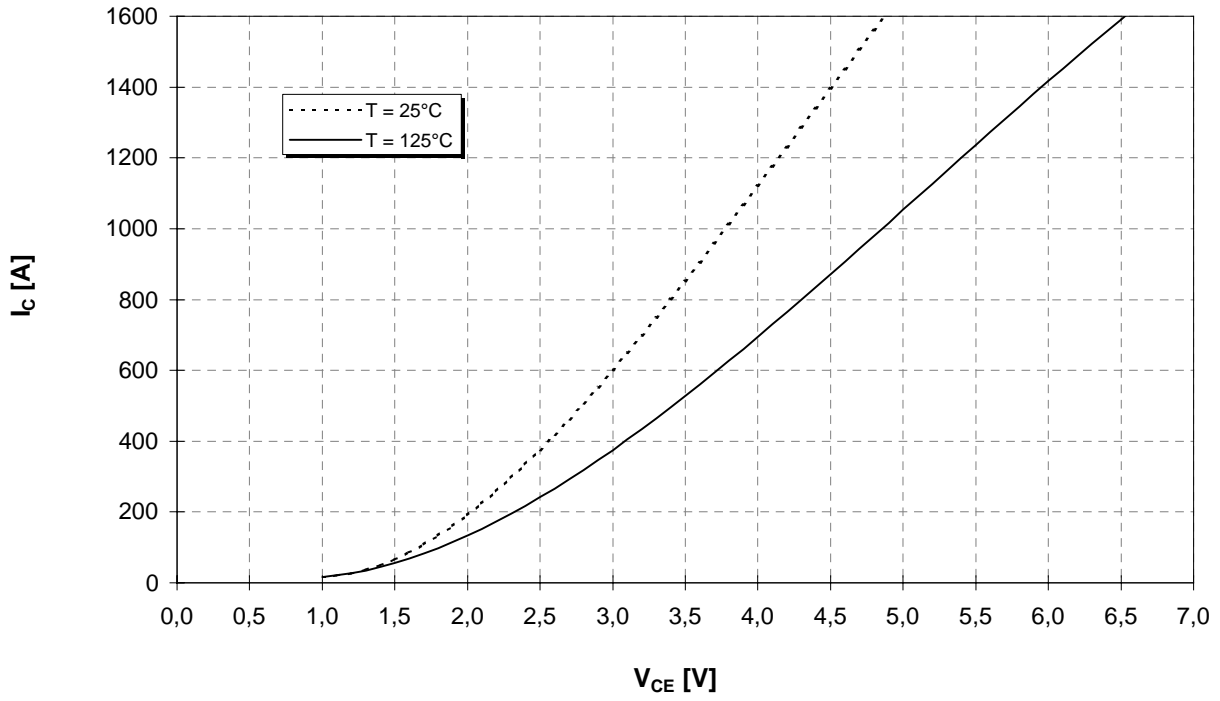
Mit dieser technischen Information werden Halbleiterbauelemente spezifiziert, jedoch keine Eigenschaften zugesichert. Sie gilt in Verbindung mit den zugehörigen Technischen Erläuterungen.

This technical information specifies semiconductor devices but promises no characteristics. It is valid in combination with the belonging technical notes.



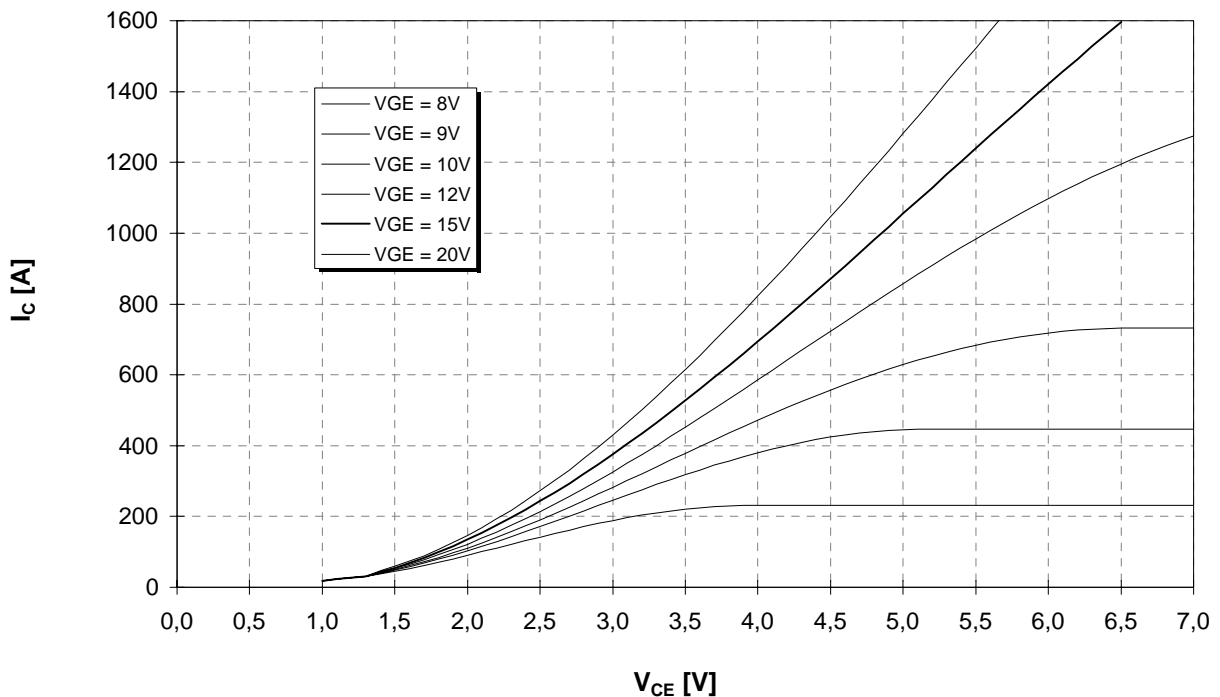
Ausgangskennlinie (typisch)  
Output characteristic (typical)

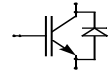
$I_C = f(V_{CE})$   
 $V_{GE} = 15V$



Ausgangskennlinienfeld (typisch)  
Output characteristic (typical)

$I_C = f(V_{CE})$   
 $T_{vj} = 125°C$

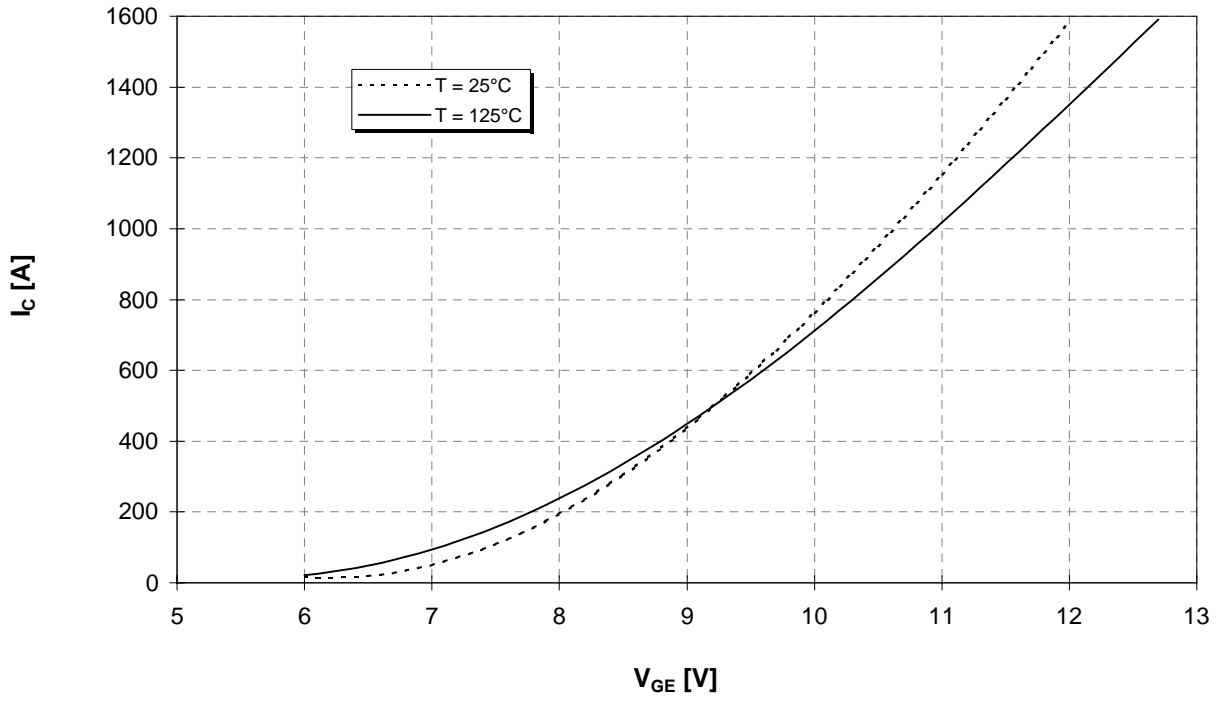




vorläufiges Datenblatt  
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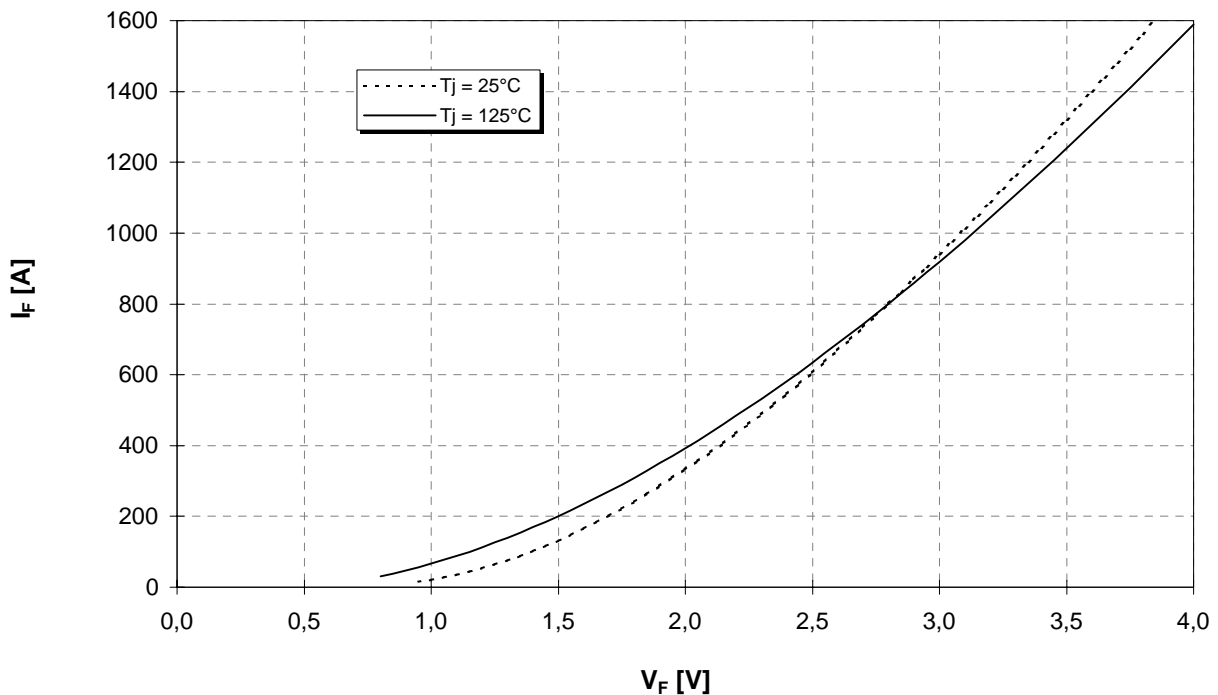
Übertragungscharakteristik (typisch)  
Transfer characteristic (typical)

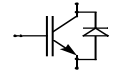
$I_C = f(V_{GE})$   
 $V_{CE} = 20V$



Durchlaßkennlinie der Inversdiode (typisch)  
Forward characteristic of inverse diode (typical)

$I_F = f(V_F)$

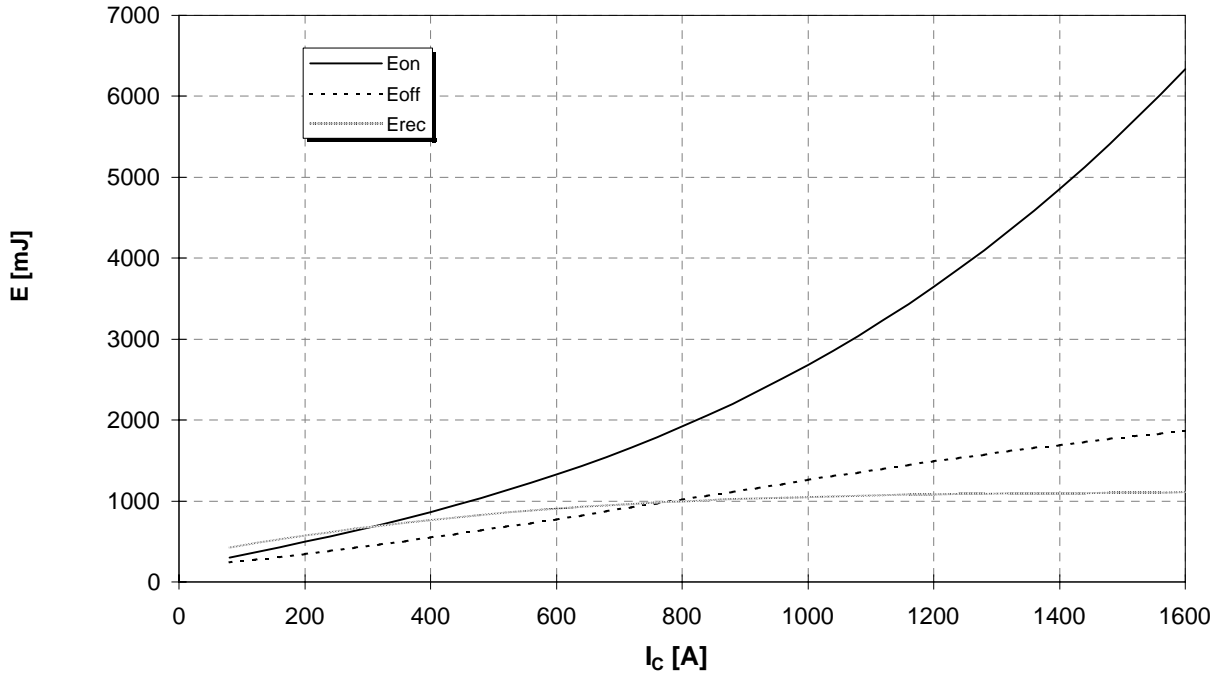




Schaltverluste (typisch)  
Switching losses (typical)

$E_{on} = f(I_C)$ ,  $E_{off} = f(I_C)$ ,  $E_{rec} = f(I_C)$

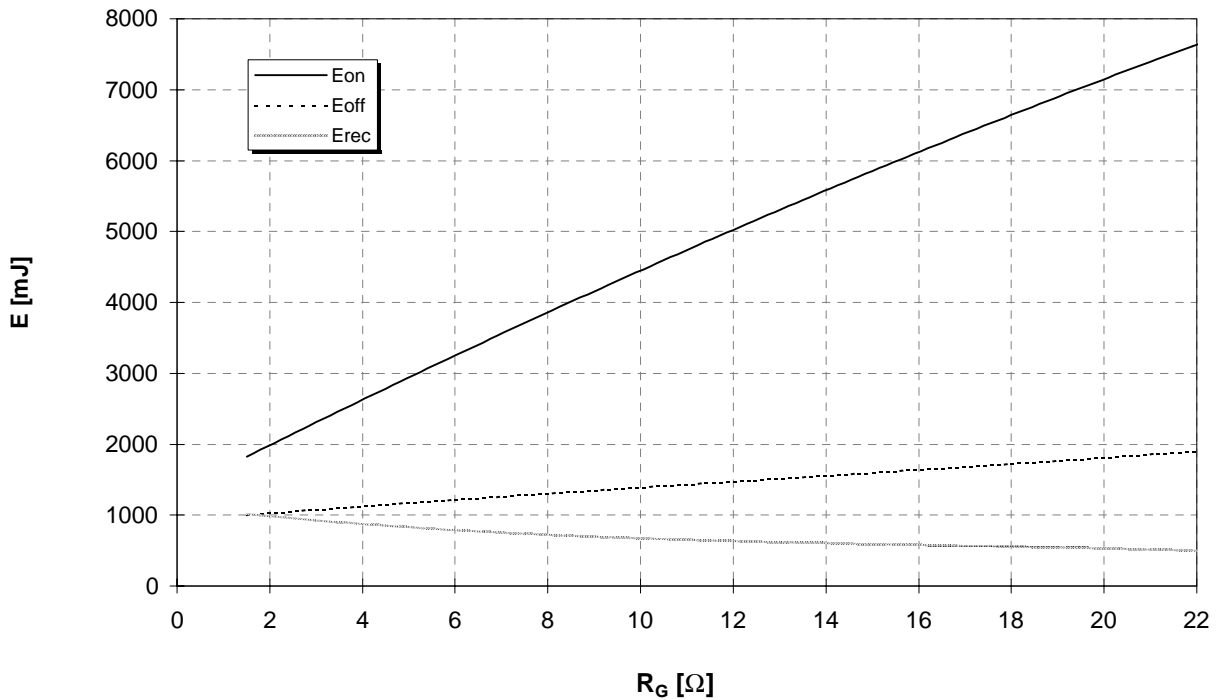
$R_{G,on} = 1,8 \Omega$ ,  $R_{G,off} = 1,8 \Omega$ ,  $C_{GE} = 150 \text{ nF}$ ,  $V_{CE} = 1800\text{V}$ ,  $T_J = 125^\circ\text{C}$

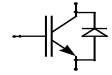


Schaltverluste (typisch)  
Switching losses (typical)

$E_{on} = f(R_G)$ ,  $E_{off} = f(R_G)$ ,  $E_{rec} = f(R_G)$

$I_C = 800 \text{ A}$ ,  $C_{GE} = 150 \text{ nF}$ ,  $V_{CE} = 1800\text{V}$ ,  $T_J = 125^\circ\text{C}$



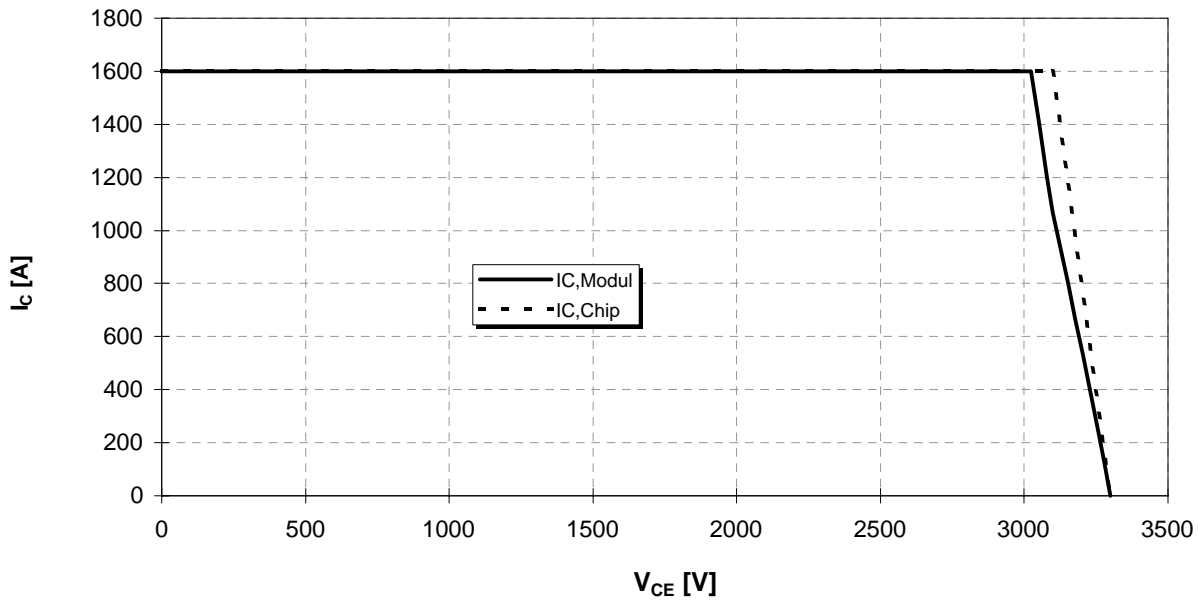


**Sicherer Arbeitsbereich IGBT (RBSOA)**

**Reverse bias safe operation area IGBT (RBSOA)**

$R_{G,off} = 1,8 \Omega$ ,  $C_{GE} = 150 \text{ nF}$

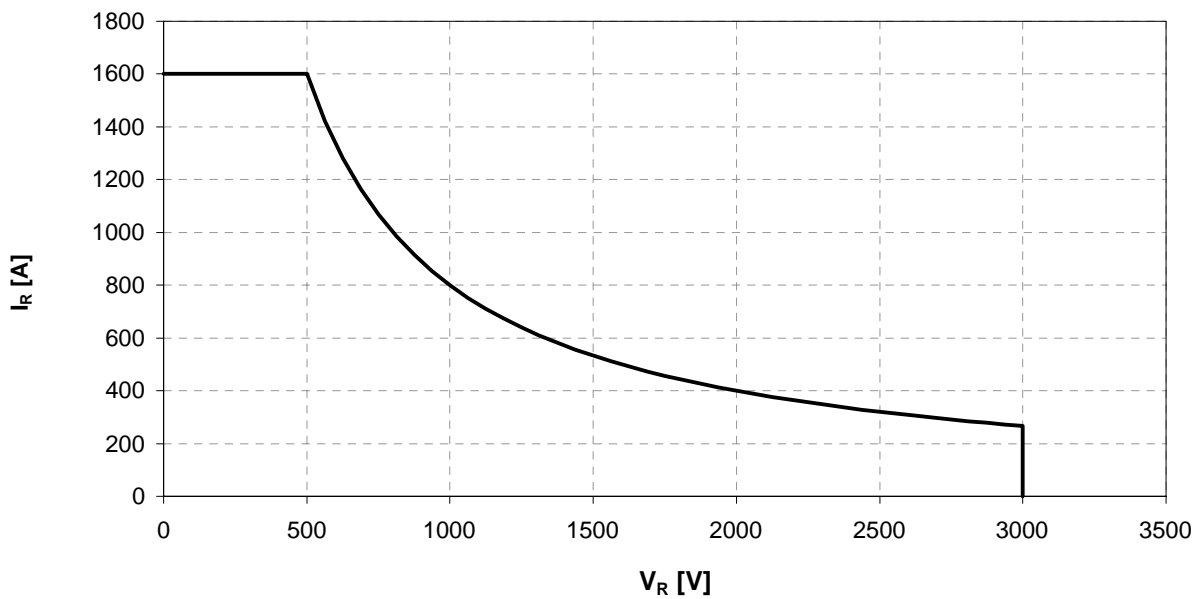
$T_{vj} = 125^\circ\text{C}$

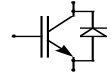


**Sicherer Arbeitsbereich Diode (SOA)**

**safe operation area Diode (SOA)**

$T_{vj} = 125^\circ\text{C}$

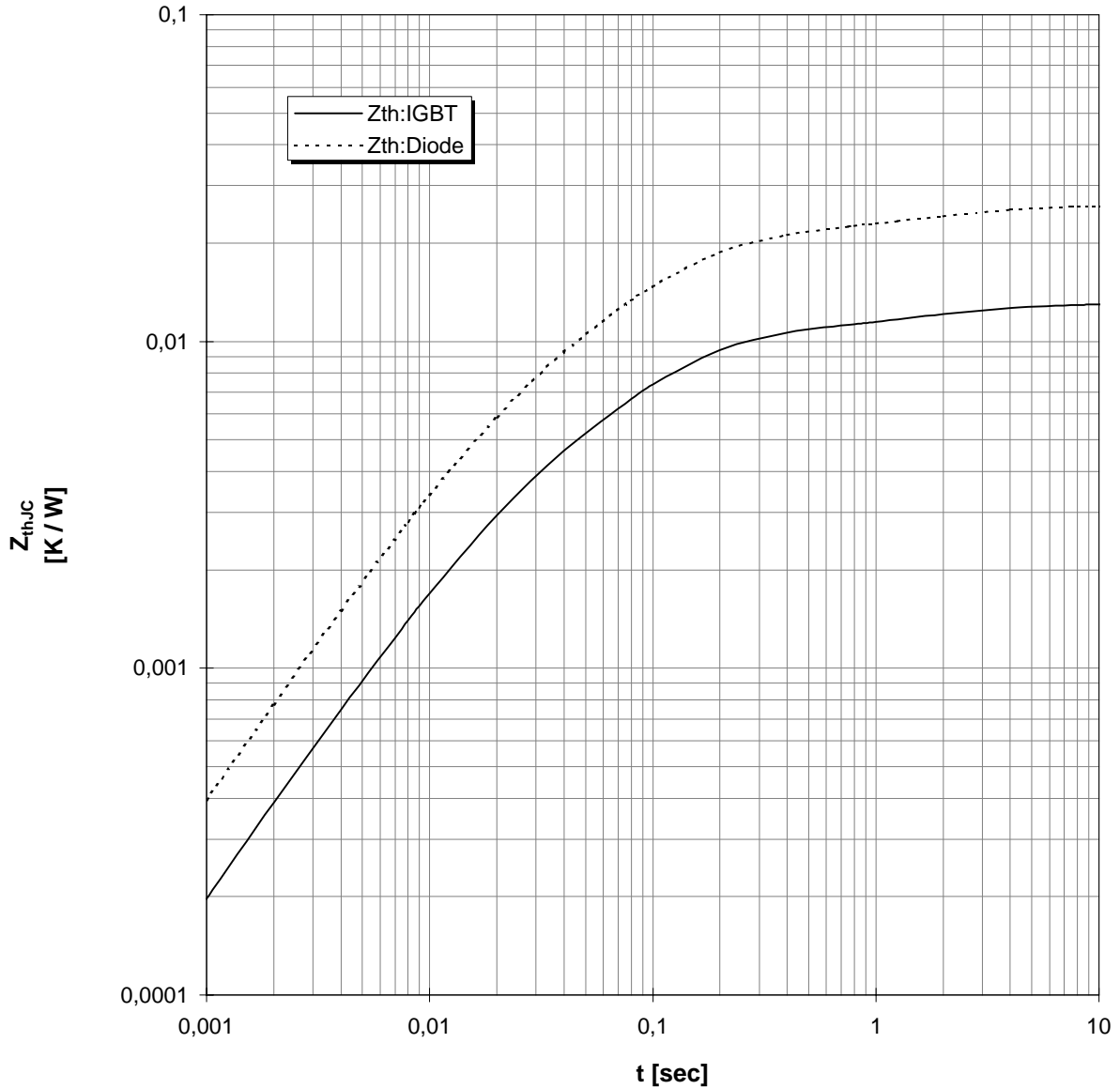




vorläufiges Datenblatt  
preliminary datasheet

Transienter Wärmewiderstand  
Transient thermal impedance

$$Z_{thJC} = f(t)$$



i	1	2	3	4
$r_i$ [K/kW] : IGBT	2,21	7,74	0,71	2,34
$\tau_i$ [sec] : IGBT	0,0185	0,0984	0,5001	2,0000
$r_i$ [K/kW] : Diode	4,42	15,48	1,42	4,68
$\tau_i$ [sec] : Diode	0,0185	0,0984	0,5001	2,0000



